

# Maximum Ratings - Q1 N-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	V <sub>DSS</sub>	20	V		
Gate-Source Voltage	V <sub>GSS</sub>	±12	V		
Steady $T_A = +25^{\circ}C$ State $T_A = +70^{\circ}C$		ID	1030 800	mA	
Continuous Drain Current (Note 7) V <sub>GS</sub> = 4.5V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	ID	1150 900	mA
Continuous Dunis Courant (Nata 7) V 4 0)/	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	ID	740 570	mA
Continuous Drain Current (Note 7) V <sub>G</sub> S = 1.8V	t<10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	ID	870 700	mA
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%	I <sub>DM</sub>	3	А		
Maximum Body Diode Continuous Current			Is	800	mA

### Maximum Ratings - Q2 P-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	V <sub>DSS</sub>	-20	V		
Gate-Source Voltage			Vgss	±8	V
Continuous Dusin Compant (Nata 7) Van 4 5)	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	lo	-700 -550	mA
Continuous Drain Current (Note 7) V <sub>GS</sub> = -4.5V	t<10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	ID	-820 -640	mA
Continuous Davis Convent (Nata 7) Vers. 4 0)/	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	-460 -350	mA
Continuous Drain Current (Note 7) V <sub>GS</sub> = -1.8V	t<10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	lo	-550 -420	mA
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	-2	Α		
Maximum Body Diode Continuous Current			Is	-800	mA

### Thermal Characteristics (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit W	
Total Power Dissipation (Note 6)	PD	0.45		
Thermal Designation to Ambient (Note 6)	Steady State	D	281	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	RөJA	210	°C/W
Total Power Dissipation (Note 7)		P <sub>D</sub>	1	W
Thermal Desistance Junction to Ambient (Note 7)	Steady State	D	129	°C/W
Thermal Resistance, Junction to Ambient (Note 7)	t<10s	RөJA	97	°C/W
Operating and Storage Temperature Range		TJ, TSTG	-55 to +150	°C

Notes:

- 6. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout. 7. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

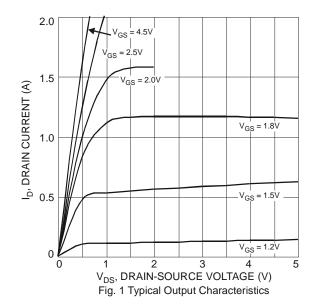


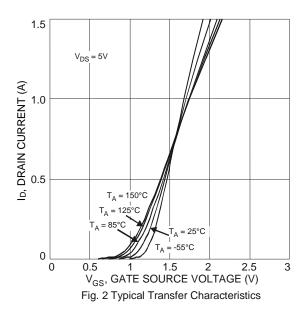
### Electrical Characteristics - Q1 N-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	_	_	V	VGS = 0V, ID = 1mA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	IDSS	_	_	100	nA	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V
Coto Source Legicare	I <sub>GSS</sub>	_	_	±1	μΑ	Vgs = ±5V, Vps = 0V
Gate-Source Leakage		_	_	±4.0		Vgs = ±8V, Vps = 0V
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	Vgs(th)	0.5		0.9	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
		_	0.3	0.48		$V_{GS} = 5.0V, I_D = 200mA$
		_	0.35	0.5		$V_{GS} = 4.5V, I_D = 200mA$
Static Drain-Source On-Resistance	D	_	0.45	0.7	Ω	$V_{GS} = 2.5V, I_D = 200mA$
Static Drain-Source On-Resistance	RDS(ON)	_	0.55	0.9		$V_{GS} = 1.8V, I_D = 100mA$
		_	0.65	1.5		$V_{GS} = 1.5V, I_D = 50mA$
		_	2	_		V <sub>G</sub> S = 1.2V, I <sub>D</sub> = 1mA
Forward Transfer Admittance	Y <sub>fs</sub>	_	1.4	_	S	V <sub>DS</sub> = 3V, I <sub>D</sub> = 200mA
Diode Forward Voltage	VsD	_	0.7	1.2	V V <sub>GS</sub> = 0V, I <sub>S</sub> = 500mA	
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	Ciss	_	37.1	_		V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	Coss	_	6.5	_	pF	
Reverse Transfer Capacitance	Crss	_	4.8	_		1 = 1.0ivii iz
Gate Resistance	Rg	_	68	_	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V
Total Gate Charge	Qg	_	0.5	_		
Gate-Source Charge	Qgs	_	0.07	_	nC	$V_{GS} = 4.5V, V_{DS} = 10V,$ $I_{D} = 250mA$
Gate-Drain Charge	Q <sub>gd</sub>	_	0.1	_		ID = 23UIIA
Turn-On Delay Time	tD(ON)	_	4.06	_		\/ 40\/ \/ 45\/
Turn-On Rise Time	t <sub>R</sub>	_	7.28	_	ns	$V_{DD} = 10V, V_{GS} = 4.5V,$ $R_L = 47\Omega, R_G = 10\Omega,$
Turn-Off Delay Time	tD(OFF)	_	13.74	_	115	$RL = 47\Omega$ , $RG = 10\Omega$ , ID = 200 mA
Turn-Off Fall Time	tF	_	10.54	_		10 - 200111A

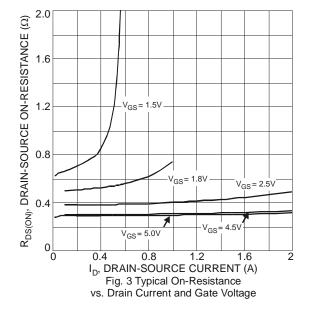
Notes:

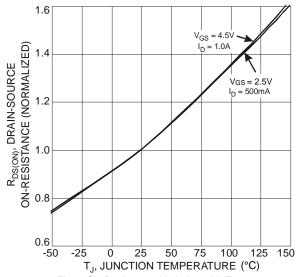
- 8. Short duration pulse test used to minimize self-heating effect.
  9. Guaranteed by design. Not subject to product testing.

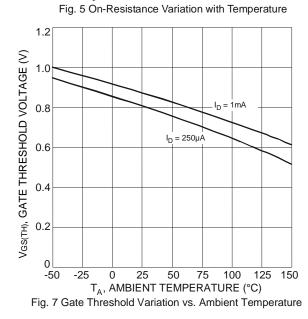












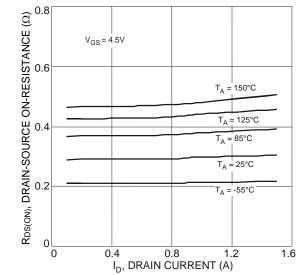


Fig. 4 Typical Drain-Source On-Resistance vs. Drain Current and Temperature

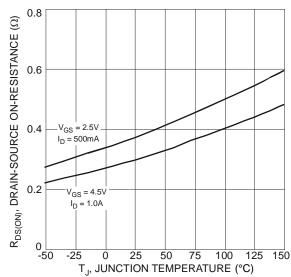


Fig. 6 On-Resistance Variation with Temperature

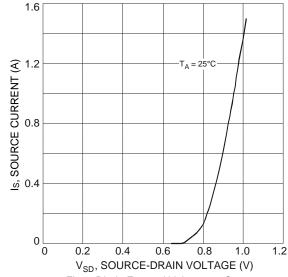
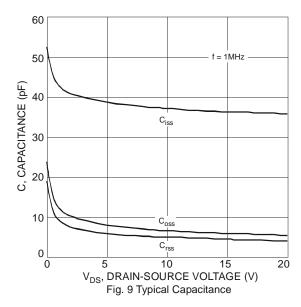
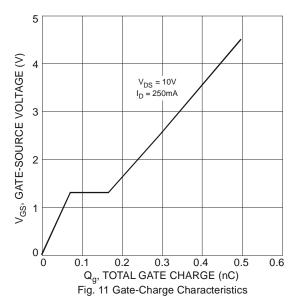


Fig. 8 Diode Forward Voltage vs. Current







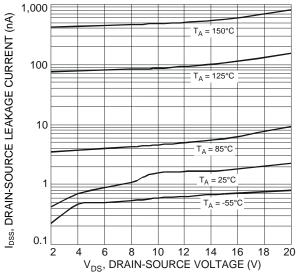
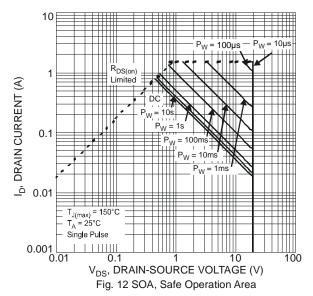


Fig. 10 Typical Drain-Source Leakage Current vs. Drain-Source Voltage



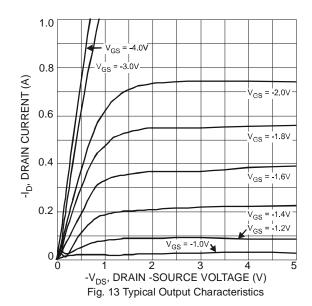


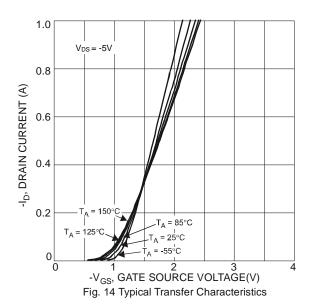
# Electrical Characteristics - Q2 P-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	_	_	V	$V_{GS} = 0V$ , $I_D = -1mA$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_		-100	nA	$V_{DS} = -20V, V_{GS} = 0V$	
Gate-Source Leakage	Igss	_		±1.0	μА	$V_{GS} = \pm 5V$ , $V_{DS} = 0V$	
Gale-Source Leakage		_	_	±5.0		$V_{GS} = \pm 8V$ , $V_{DS} = 0V$	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-0.5		-1.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
		_	0.67	0.97		$V_{GS} = -5V, I_{D} = -100mA$	
		_	0.7	1.0		$V_{GS} = -4.5V, I_{D} = -100mA$	
Static Drain-Source On-Resistance	Dragov.	_	0.9	1.5	Ω	$V_{GS} = -2.5V, I_D = -80mA$	
Static Dialii-Source Off-Resistance	RDS(ON)	_	1.2	2.0	12	$V_{GS} = -1.8V, I_{D} = -40mA$	
			1.5	3.0		$V_{GS} = -1.5V, I_{D} = -30mA$	
			5	_		$V_{GS} = -1.2V, I_{D} = -1mA$	
Forward Transfer Admittance	Y <sub>fs</sub>	_	0.7	_	S	$V_{DS} = -3V, I_{D} = -100mA$	
Diode Forward Voltage	$V_{SD}$		-0.75	-1.2	V	$V_{GS} = 0V, I_{S} = -330mA$	
DYNAMIC CHARACTERISTICS (Note 9)	DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	Ciss	_	46.1	_		V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss		7.2	_	pF		
Reverse Transfer Capacitance	Crss		4.9	_			
Gate Resistance	$R_g$		14.3	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$	
Total Gate Charge (VGS = -4.5V)	Qg	_	0.5	_		V <sub>DS</sub> = -10V, I <sub>D</sub> = -250mA	
Total Gate Charge (V <sub>GS</sub> = -10V)	Qg	_	0.85	_	nC		
Gate-Source Charge	Qgs	_	0.09	_	nc nc		
Gate-Drain Charge	Q <sub>gd</sub>	_	0.09	_			
Turn-On Delay Time	t <sub>D(ON)</sub>		8.5	_		V 0V V 0.5V	
Turn-On Rise Time	t <sub>R</sub>	_	4.3	_	] no	$V_{DD} = -3V$ , $V_{GS} = -2.5V$ ,	
Turn-Off Delay Time	tD(OFF)		20.2	_	ns	$R_L = 300\Omega$ , $R_G = 25\Omega$ , $I_D = -100$ mA	
Turn-Off Fall Time	tF	_	19.2	_		ID = - IOOIIIA	

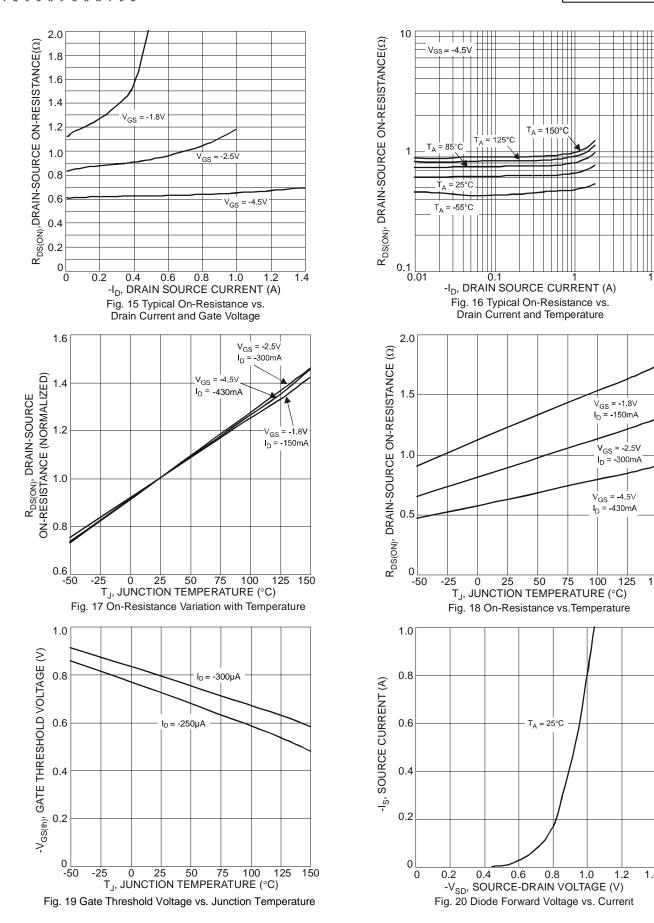
Notes:

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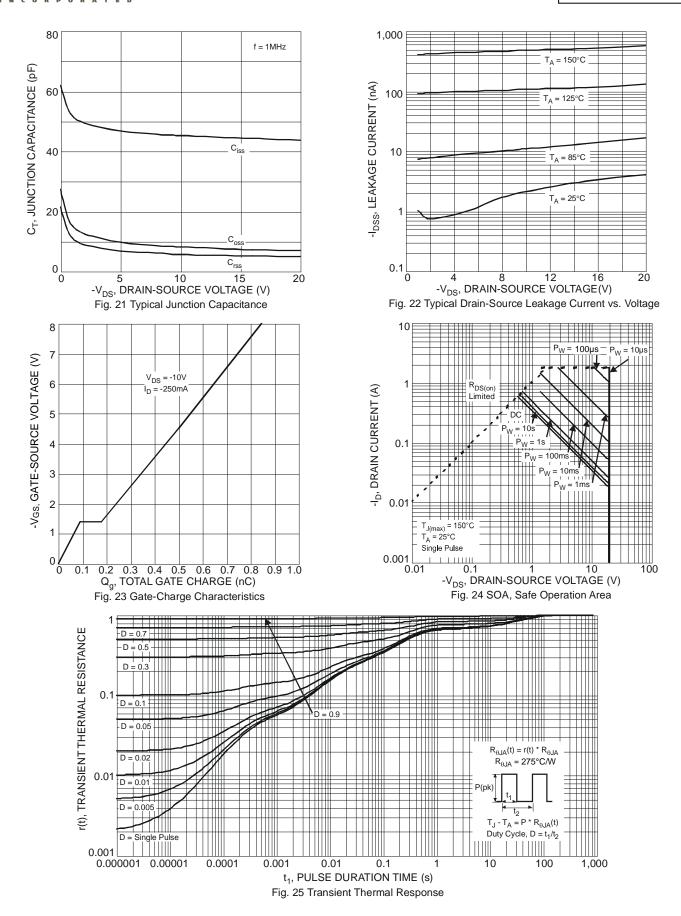










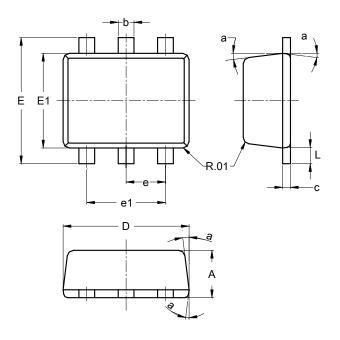




### **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

### **SOT563**

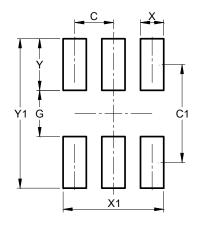


SOT563						
Dim	Min	Max	Тур			
Α	0.55	0.60	0.60			
b	0.15	0.30	0.20			
С	0.10	0.18	0.11			
D	1.50	1.70	1.60			
E	1.55	1.70	1.60			
E1	1.10	1.25	1.20			
е			0.50			
e1	0.90	1.10	1.00			
L	0.10	0.30	0.20			
а	8°	9°	7°			
All Dimensions in mm						

# **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### **SOT563**



Dimensions	Value (in mm)			
С	0.500			
C1	1.270			
G	0.600			
Х	0.300			
X1	1.300			
Y	0.670			
V1	1 040			



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